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Biomedical Imaging, 2002. Proceedings. 2002 IEEE International Symposium on 10 July 2002

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Nuclear Science, IEEE Transactions on , Volume: 45 Issue: 3 , June 1998

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INFOCOM 2002. Twenty-First Annual Joint Conference of the IEEE Computer and Communications Societies. Proceedings. IEEE , Volume: 3 , 23-27 June 2002

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